

**Search Notes**

Application/Control No.

10/773,044

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

HIROTSGU ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	51	03.15.05	Mr
	52	—	—
	65	—	—
	60	—	—
	63		—
	124		—
	30		—
360	46		—
	67	—	—
	68	—	—

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	03.15.05	Mr
Consulted with Than Lam	03.15.05	Mr
Consulted with Steve Mottola	03.15.05	Mr

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner